Applicant(s)/Patent Under Application/Control No. Reexamination 10/723,002 TENG ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2851 Magda Cruz **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY 353/122 US-6,056,408 05-2000 Kobayashi, Kiwamu Α US-6,339,434 01-2002 West et al. 345/667 В * US-2002/0008697 01-2002 Deering, Michael F. 345/418 С US-D US-Ε US-F US-G

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